

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1868	Feb-97	9702 A4	ANAM, K.	DN636093AAB	0.8μ NITRIDE	20 TSSOP

STRESS/JOB NO.

**READPOINT
(Sample Size/No. of Fails)**

Preconditioning (P/C):
HTC Vapor Phase
P-19069

Electrical Cum %
233/0 0.0%

Sonoscan
P-19111

Post Vapor Phase
4/0

Infant / High Voltage Life
125°C, 7.0 V.
P-19112, P-19240

<u>48 Hr</u>	<u>336 Hr</u>	<u>1KHr</u>	<u>*Failure Rate</u>
227/0	77/0	77/1	67 Fits
		F1	

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle
-55°C to +125°C
P-19241

<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
35/0	35/0	0.0%

Biased Moisture
85°C/85% RH, 5.5 V.
P-19242

<u>274 Hr</u>	<u>959 Hr</u>	<u>Cum %</u>
77/0	77/0	0.0%

Autoclave
121°C/100% RH, 2 Atmos
P-19243

<u>96 Hr</u>	<u>Cum %</u>
35/0	0.0%

Failure Mode

Failure Analysis

F1: Total Resistance

In process